

Notice of References Cited

Application/Control No.

10/551,901

Applicant(s)/Patent Under
Reexamination
MIURA ET AL.

Examiner

Jeffrey T. Palenik

Art Unit

1615

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0058956	03-2004	Akiyama et al.	514/318
*	B	US-2003/0121453	07-2003	Iwahashi et al.	106/502
	C	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 1 323 786 A1	07-2003	EP	Iwahashi et al.	C09D 7/00
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	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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